

Search Notes

Application/Control No.

10/696,384

Examiner

Simon J. Oh

Applicant(s)/Patent under
Reexamination

CHAUBAL ET AL

Art Unit

1618

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR